

<b>Notice of References Cited</b>	Application/Control No. 1	Applicant(s)/Patent Under Reexamination EGAMI ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,245,902 A	01-1981	Cataldo et al.	396/502
*	B	US-4,510,381 A	04-1985	Fukatsu, Kunio	194/350
*	C	US-4,540,106 A	09-1985	Fukatsu, Kunio	221/13
*	D	US-4,942,464 A	07-1990	Milatz, Erhard	348/150
*	E	US-5,253,167 A	10-1993	Yoshida et al.	705/43
*	F	US-5,454,332 A	10-1995	Fennelly et al.	109/19
*	G	US-2002/0073032 A1	06-2002	Holmes et al.	705/43
*	H	US-6,510,985 B1	01-2003	Clark et al.	235/379
*	I	US-6,583,864 B1	06-2003	Stanners, Anthony J.	356/71
*	J	US-6,601,045 B1	07-2003	DePietro et al.	705/43
*	K	US-2003/0179290 A1	09-2003	Frazzitta et al.	348/61
*	L	US-2003/0180039 A1	09-2003	Kakou et al.	396/427
*	M	US-2004/0026498 A1	02-2004	Fujioka, Toshinori	235/379

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP410188079	07-1998	Japan	Kaneko et al.	
	O	JP358192170A	11-1983	Japan	Fukatsu	
	P	JP09270050	10-1997	Japan	Osawa et al.	
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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<b>Notice of References Cited</b>	Application/Control No. 10/747,673	Applicant(s)/Patent Under Reexamination EGAMI ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0060980 A1	04-2004	Shibata et al.	235/381
*	B	US-6,731,778 B1	05-2004	Oda et al.	382/118
*	C	US-2004/0164141 A1	08-2004	Egami et al.	235/379
*	D	US-6,978,928 B2	12-2005	Shibata et al.	235/381
*	E	US-2006/0043167 A1	03-2006	Fujioka, Tshinori	235/379
*	F	US-2006/0180653 A1	08-2006	Meek et al.	235/379
*	G	US-2007/0063838 A1	03-2007	Yuzik, Rodney J.	340/540
*	H	US-2007/0081540 A1	04-2007	Crowell et al.	370/395.1
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N					
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	P					
	Q					
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